







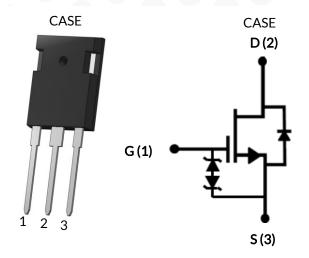








UJ3C120080K3S



Part Number	Package	Marking
UJ3C120080K3S	TO-247-3L	UJ3C120080K3S







1200V-80m Ω SiC FET

Rev. F, November 2022

Description

This SiC FET device is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the TO-247-3L package, this device exhibits ultralow gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads, and any application requiring standard gate drive.

Features

- \bullet Typical on-resistance $R_{DS(on),typ}$ of $80m\Omega$
- Maximum operating temperature of 175°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- ESD protected: HBM class 2 and CDM class C3

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating















Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		1200	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current ¹	I _D	T _C = 25°C	33	Α
Continuous drain current		T _C = 100°C	24	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	77	А
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =2.8A	58.5	mJ
Power dissipation	P _{tot}	T _C = 25°C	254.2	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J, T_{STG}		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	T _L		250	°C

- 1. Limited by $T_{J,max}$
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Offics
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.45	0.59	°C/W













Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	UIIILS
Drain-source breakdown voltage	BV _{DS}	V_{GS} =0V, I_D =1mA	1200			V
		V _{DS} =1200V,		10	75	- μΑ
Total drain leakage current		$V_{GS}=0V, T_J=25$ °C				
Total di alli leakage cui l'elli	I _{DSS}	V _{DS} =1200V,		E0		
		$V_{GS}=0V, T_{J}=175^{\circ}C$		50		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C,		6	± 20	μΑ
		V _{GS} =-20V / +20V				
Drain-source on-resistance	R _{DS(on)}	$V_{GS}=12V, I_{D}=20A,$		80	100	mΩ
		T _J =25°C				
		V_{GS} =12V, I_{D} =20A,		130		
		T _J =125°C				
		V_{GS} =12V, I_{D} =20A,		172		
		T _J =175°C				
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_{D} =10mA	4	5	6	V
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Linita		
Parameter			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C =25°C			33	Α
Diode pulse current ²	I _{S,pulse}	T _C =25°C			77	Α
Forward voltage	V _{FSD}	V_{GS} =0V, I_{S} =10A, T_{J} =25°C		1.5	2	V
		V _{GS} =0V, I _S =10A, T _J =175°C		2		
Reverse recovery charge	Q _{rr}	V_{DS} =800V, I_{S} =20A, V_{GS} =0V, $R_{G_{L}EXT}$ =10 Ω		180		nC
Reverse recovery time	t _{rr}	di/dt=2200A/μs, Τ _J =150°C		30		ns















Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Offics
Input capacitance	C_{iss}	V _{DS} =100V, V _{GS} =0V - f=100kHz -		1500		
Output capacitance	C_{oss}			100		pF
Reverse transfer capacitance	C_{rss}	1-100KH2		2.1		
Effective output capacitance, energy related	$C_{oss(er)}$	V_{DS} =0V to 800V, V_{GS} =0V		59		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS} =0V to 800V, V_{GS} =0V		136		pF
C _{OSS} stored energy	E_{oss}	V_{DS} =800V, V_{GS} =0V		19		μЈ
Total gate charge	Q_{G}	V_{DS} =800V, I_{D} =20A, V_{GS} = -5V to15V		51		
Gate-drain charge	Q_{GD}			11		nC
Gate-source charge	Q_{GS}			19		
Turn-on delay time	$t_{d(on)}$	$\begin{array}{c} V_{DS}\text{=}800\text{V, }I_{D}\text{=}20\text{A, Gate} \\ Driver =-5\text{V to }+15\text{V,} \\ Turn\text{-}on R_{G,EXT}\text{=}1\Omega, \\ Turn\text{-}off R_{G,EXT}\text{=}20\Omega \\ Inductive Load, \\ FWD: UJ2D1215T \\ T_{J}\text{=}150^{\circ}\text{C} \end{array}$		22		ns
Rise time	t _r			14		
Turn-off delay time	$t_{\text{d(off)}}$			61		
Fall time	t_f			14		
Turn-on energy	E _{ON}			260		
Turn-off energy	E _{OFF}			108		μЈ
Total switching energy	E _{TOTAL}			368		







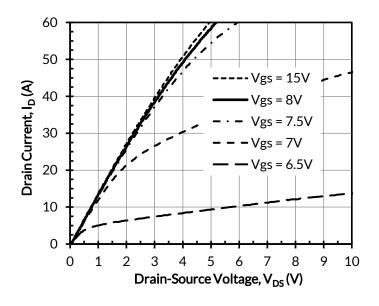








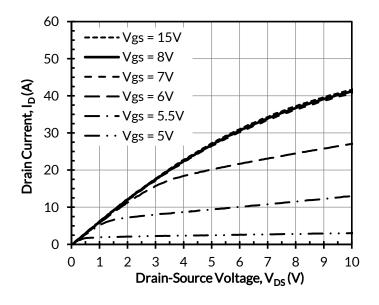
Typical Performance Diagrams



60 50 Drain Current, I_D (A) 40 Vgs = 15V 30 Vgs = 8V Vgs = 7V 20 Vgs = 6.5V **-** Vgs = 6V 10 0 0 1 2 10 5 Drain-Source Voltage, V_{DS} (V)

Figure 1. Typical output characteristics at $T_J = -55$ °C, tp < 250 μ s

Figure 2. Typical output characteristics at $T_J = 25$ °C, tp < 250μ s



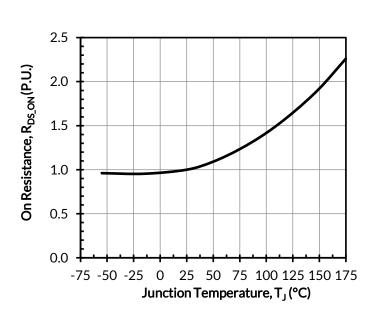


Figure 3. Typical output characteristics at T_J = 175°C, tp < 250 μ s

Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_D = 20A





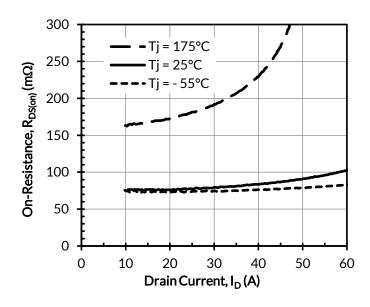








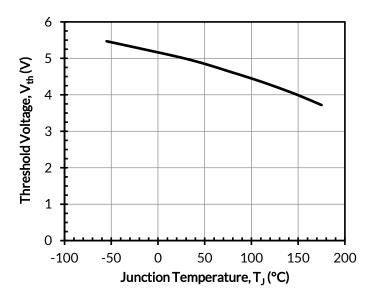




Tj = -55°C Tj = 25°C Drain Current, I_D (A) Tj = 175°C Gate-Source Voltage, V_{GS} (V)

Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at $V_{DS} = 5V$



Gate-Source Voltage, V_{GS} (V) -5 Gate Charge, Q_G (nC)

Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_D = 10mA

Figure 8. Typical gate charge at V_{DS} = 800V and I_{D} = 20A















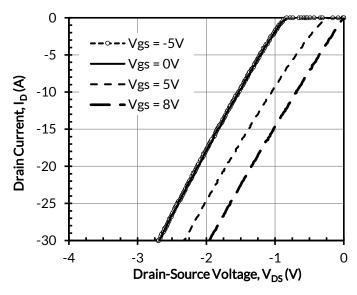


Figure 9. 3rd quadrant characteristics at $T_J = -55$ °C

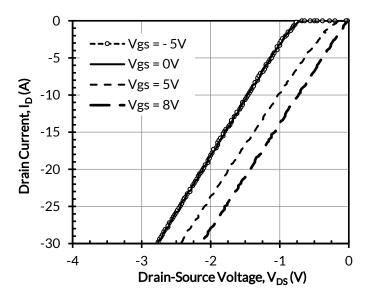


Figure 10. 3rd quadrant characteristics at T_J = 25°C

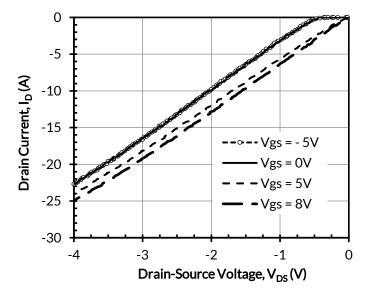


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

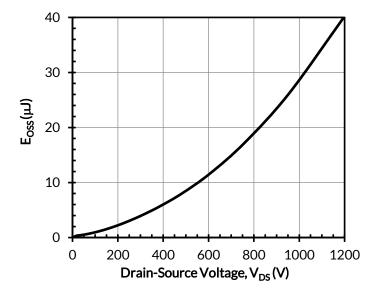


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$





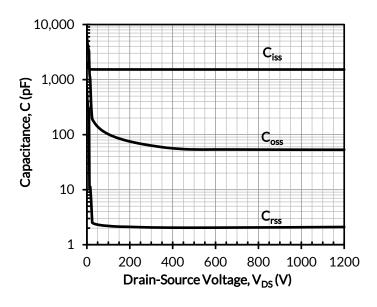








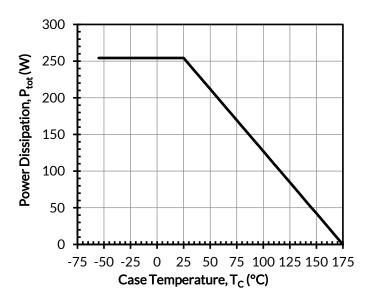




35 30 DC Drain Current, I_D (A) 25 20 15 10 5 0 25 50 75 100 125 150 175 -75 -50 -25 0 Case Temperature, T_C (°C)

Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

Figure 14. DC drain current derating



1 Thermal Impedance, $Z_{\theta JC}$ (°C/W) 0.1 D = 0.5D = 0.3**-** D = 0.1 0.01 - D = 0.05 ···· D = 0.02 -D = 0.01Single Pulse 0.001 1.E-06 1.E-05 1.E-04 1.E-03 1.E-02 1.E-01 Pulse Time, t_p (s)

Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance















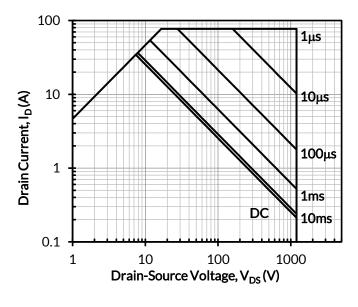


Figure 17. Safe operation area at T_C = 25°C, D = 0, Parameter t_p

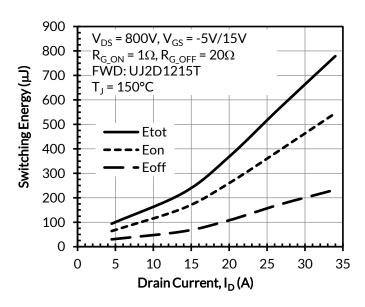


Figure 18. Clamped inductive switching energy vs. drain current at $T_J = 150$ °C

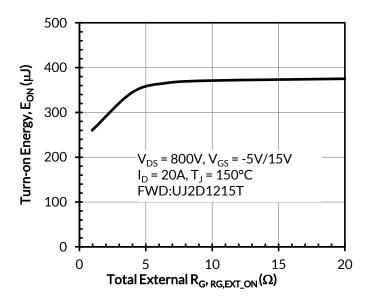


Figure 19. Clamped inductive switching turn-on energy vs. R_{G,EXT_ON}

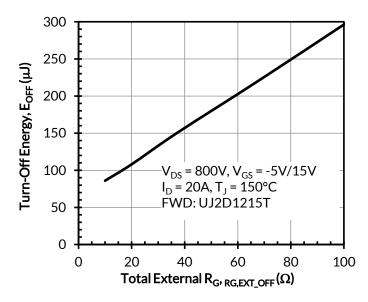


Figure 20. Clamped inductive switching turn-off energy vs. R_{G,EXT_OFF}















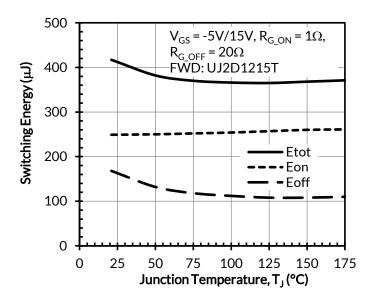


Figure 21. Clamped inductive switching energy vs. junction temperature at V_{DS} = 800V and I_D = 20A

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (C_{oss}), and reverse recovery charge (C_{oss}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at www.unitedsic.com













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C3M0045065K E3M0120090J C3M0065090J-TR C3M0120100J C3M0075120J DMWS120H100SM4 DMWSH120H28SM4
DMWSH120H90SM4 DMWSH120H90SM4Q DMWSH120H28SM4Q DMWSH120H90SCT7Q DMWSH120H28SM3
DMWSH120H43SM3 DMWSH120H90SM3 DMWSH120H28SM3Q DMWSH120H90SM3Q DIF120SIC053-AQ DIW120SIC059-AQ
G2R1000MT17D G3R60MT07K G2R50MT33K G3R12MT12K G3R160MT12D G3R160MT12J-TR G3R160MT17D G3R40MT17J-TR
G3R20MT12K G3R20MT12N G3R20MT17K G3R20MT17N G3R30MT12J-TR G3R30MT12K G3R350MT12D G3R40MT12D
G3R40MT12J